

Notice of References Cited

Application/Control No. 09/460,844

09/460,844

Applicant(s)/Patent Under Reexamination
HEKMATPOUR, AMIR

Examiner

Hugh Jones

Art Unit

2128

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US- 5,808,919	9-1998	Preist et al.	702/108
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kirsch et al.; "Applying Bayesian networks to fault diagnosis"; IEEE Proc. 3 rd IEEE Conf Control Appl.; pp. 895-900; 8/1994.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.